Sixty-third Denver X-ray Conference and selected Advances in X-ray Analysis papers for the June *Powder Diffraction* issue

As part of the 63rd Annual Denver X-ray Conference (DXC), proceedings are published in *Advances in X-ray Analysis* (AXA). After reviewing 32 XRD (X-ray Diffraction), XRF (X-ray Fluorescence), and related fields AXA papers, five were selected for publication in *Powder Diffraction*. The five selected papers highlight interesting developments in materials analysis. Together with the regular published papers in this June issue of *Powder Diffraction* readers are provided with the opportunity to learn about current topics in a variety of materials characterization applications.

The five selected AXA papers and authors are:

Stress determination through diffraction: establishing the link between kröner and voigt/reuss limits; C. E. Murray, J. L. Jordan-Sweet, S. W. Bedell, E. T. Ryan

Crystal orientation measurements using SEM-EBSD under unconventional conditions; K. Kunze

Comparison of different excitation modes for the analysis of light elements with a TXRF vacuum chamber; J. Prost, P. Wobrauschek, C. Streli

Secondary excitation process for quantitative confocal 3D-XRF analysis; K. Tsuji, A. Tabe, P. Wobrauscheck, C. Streli

A new methodical approach based on compton scattering and XRF: quantitative analysis of CO_2 and loss on ignition in quicklime; M. Inoue, Y. Yamada, M. Kitamura, N. Gotoh, N. Kawahara, M. Mantler

The talents of many people are required to make the addition of these AXA papers for publication in *Powder Diffraction* a reality. Besides the authors themselves, we thank the DXC organizing committee members and others for their reviews of these articles. We would also like to thank the DXC coordinator Denise Zulli and *Powder Diffraction* managing editor Nicole Ernst-Boris for all of their hard work in making this publication a reality.

We hope you enjoy this compilation of manuscripts and we look forward to seeing you at the 64th Annual DXC in Westminster, Colorado 3–7 August 2015 (www.dxcicdd.com). This year's gathering will be a joint meeting of the Denver X-ray and the International Total Reflectance X-ray Fluorescence Conferences. There will be XRD, XRF, and TXRF (Total Reflectance X-ray Fluorescence) workshops, the plenary session is "TXRF Around the World", and there will be a session on new developments in XRD and XRF instrumentation. In addition there will be XRD technical sessions covering high flux sources, stress analysis, applied materials analysis, Rietveld refinement, energy materials, and general XRD; XRF sessions covering quantitative analysis, environmental and geological materials analysis, fusion and industrial applications, and general XRF; TXRF sessions covering standardization, environmental materials analysis, biological materials analysis, semiconductor materials analysis, and synchrotron radiation TXRF. Evening events include two poster sessions, and a vendor sponsored reception. This meeting provides a unique opportunity to learn from experts in X-ray, neutron, and electron scattering techniques, meet with vendors to find out what is new in instrumentations and software, and network with colleagues working in the high energy scattering community.

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